

			02.11.2011
RefMat No 5	56		Category 1 Depth profiling resolutio
	COMAR		Category 2 Film Thickness
	47.569 × 122-5-75	Included in OMAR Database:	Category 3
	7.3	Green 1> YES Blue 0> NO	Category 4
		Dide 0 -> 140	Category 5
Type_of_RefMat: CRM			
Name of RM: NMIJ CRM 5204-a			
Description Ultrathin Silicon dioxide film: 3.49 nm (0.19 nm); control the precision of analysis and to regulate measurement condition in depth profile analysis by ion			
<mark>sputterir</mark>		,	
Link http://www.nmij.jp/english/service/C/crm/2_E.pdf			
	Certified (Qantities	
	Film Thickness	MeanValue	3,49 nm Uncertainty 0,2 nm
		MeanValue	nm Uncertainty
Calibration of	AES		Characterised by grazing incidence x-ray refle
Calibration of	ESCA		Characterised by
Calibration of	SIMS		Characterised by
Calibration of	ToF-SIMS		Characterised by
Calibration of			Characterised by
2 Provider No Provider No 16			
Provider No	16 Web address http	o://www.nmij.jp/er	nglish/
Provider NMIJ (National Metrology Institute of Japan); AIST Tsukuba Central 5			
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